

Reliability Data Report Product Family R531

LT1965 / LT3008 / LT3009 / LT3015 / LT3022 / LT3029 / LT3050 / LT3060 / LT3080 / LT3082 / LT3083 / LT3085 / LT3092



Reliability Data Report Report Number: R531 Report generated on: Tue Oct 16 11:27:21 PDT 2012

OPERATING LIFE TEST									
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE HRS	No. of FAILURES				
		CODE	CODE	(+125°C) ¹	2,3				
QFN/DFN	539	0713	0943	539	0				
SSOP/TSSOP	77	0941	0941	77	0				
TO-3	231	1034	1034	616	0				
SOIC/SOT/MSOP	266	0813	1029	248	0				
Totals	1,113	-	-	1,480	0				
PRESSURE CO	OKER TEST A	T 15 PSIG , +12	1 DEG C						
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE HRS	No. of FAILURE				
		CODE	CODE						
QFN/DFN	2190	0739	1118	447	0				
SSOP/TSSOP	49	1045	1045	1	0				
SOIC/SOT/MSOP	3900	0739	1120	296	0				
TO-220	100	1045	1115	2	0				
Totals	6,239	-	-	746	0				
TEMP CYCLE	FROM -65 TO 1	50 DEG C							
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE	No. of FAILURE				
		CODE	CODE	CYCLES					
QFN/DFN	1923	0739	1118	1023	0				
SSOP/TSSOP	100	1045	1046	10	0				
SOIC/SOT/MSOP	1962	0739	1120	888	0				
TO-220	100	1045	1115	10	0				
Totals	4,085	-	-	1,931	0				
THERMAL SHO	OCK FROM -65	TO 150 DEG C							
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE	No. of FAILURE				
		CODE	CODE	CYCLES					
QFN/DFN	1798	0739	1118	1026	0				
SSOP/TSSOP	100	1045	1046	10	0				
SOIC/SOT/MSOP	2184	0739	1120	941	0				
TO-220	99	1045	1115	9	0				
Totals	4,181	-	-	1,986	0				
HIGH TEMPER	ATURE BAKE	AT 150 DEG C							
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE HRS	No. of FAILURE				
		CODE	CODE						
QFN/DFN	358	0739	0820	358	0				
(JEIN/LIEIN I		0.00	1 2220		 				
SOIC/SOT/MSOP	535	0739	1033	535	0				

(1) Assumes Activation Energy = 1.0 Electron Volts
(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =1.24 FITS
(3) Mean Time Between Failure in Years = 92161.22
Note 1: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL 3/4 Preconditioning



Reliability Data Report Report Number: R531 Report generated on: Tue Oct 16 11:27:21 PDT 2012

HIGH TEMPERATURE BAKE AT 175 DEG C								
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE	NEWEST DATE	K DEVICE HRS	No. of FAILURES			
QFN/DFN	611	0552	0943	1253	0			
SOIC/SOT/MSOP	385	0739	0943	385	0			
Totals	996	-	-	1,638	0			